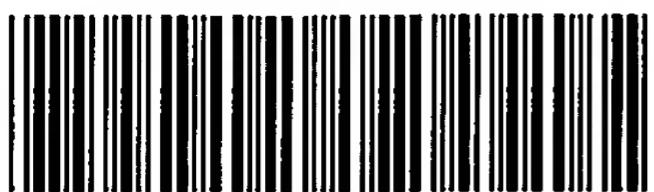


## **Search Notes**



**Application/Control No.**

**Applicant(s)/Patent under  
Reexamination**

10/632,316

SHAH ET AL.

## Examiner

## Art Unit

TAN X. DINH

2627

**SEARCHED**

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## INTERFERENCE SEARCHED

<b>INTERFERENCE SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>